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### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

### Details

E·XFI

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	125
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-3pq160

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Power Matters."

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- The Transient Current, page 13 is new (SAR 36930).
- Package names were revised according to standards established in *Package Mechanical Drawings* (SAR 34774)

## 1.7 Revision 9.0

The following is a summary of the changes in revision 9.0 of this document

In Table 20, page 23, the limits in VI were changed from -0.5 to VCCI + 0.5 to -0.5 to VCCA + 0.5

In Table 22, page 25, V<sub>OH</sub> was changed from 3.7 to 2.4 for the min in industrial and military. V<sub>IH</sub> had V<sub>CCI</sub> and that was changed to VCCA

## 1.8 Revision 6.0

The following is a summary of the changes in revision 6.0 of this document.

- The Ease of Integration, page 1 was updated
- The Temperature Grade Offerings, page 5 is new
- The Speed Grade Offerings, page 5 is new
- The General Description, page 6 was updated
- The MultiPlex I/O Modules, page 11 was updated
- The User Security, page 12 was updated
- Table 6, page 13 was updated
- The Power Dissipation, page 14 was updated.
- The Static Power Component, page 14 was updated
- The Equivalent Capacitance, page 15 was updated
- Figure 13, page 17 was updated
- Table 10, page 18 was updated.
- Figure 14, page 18 was updated.
- Table 11, page 19 was updated.



## 3 40MX and 42MX FPGAs

## 3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi's patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

## 3.2 MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

### 3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.



## 3.3.7 Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200 µs to allow for charge pumps to power up, and device initialization will begin.

## 3.4 **Power Dissipation**

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation.

### 3.4.1 General Power Equation

P = [ICCstandby + ICCactive]\*VCCI + IOL\*VOL\*N + IOH\*(VCCI - VOH)\*M

EQ 1

where:

- ICCstandby is the current flowing when no inputs or outputs are changing.
- ICCactive is the current flowing due to CMOS switching.
- IOL, IOH are TTL sink/source currents.
- VOL, VOH are TTL level output voltages.
- N equals the number of outputs driving TTL loads to VOL.
- M equals the number of outputs driving TTL loads to VOH.

Accurate values for N and M are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

### 3.4.2 Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

### 3.4.3 Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

The power dissipated by a CMOS circuit can be expressed by the equation:

$$Power(\mu W) = C_{EO}^* VCCA2^* F(1)$$

where:

C<sub>EQ</sub> = Equivalent capacitance expressed in picofarads (pF)

EQ 2



# Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T<sub>J</sub> = 70°C)

		–3 SI	beed	–2 S	beed	–1 Sp	eed	Std S	Speed	–F S	peed	
Paramet	er / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
Input Mo	odule Propagation Delays											
t <sub>INYH</sub>	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t <sub>INYL</sub>	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns



		-3 S	peed	–2 S	beed	–1 S	peed	Std S	Speed	–F Sp	peed	
Parame	ter / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS C	Dutput Module Timing <sup>5</sup>											
t <sub>DLH</sub>	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t <sub>DHL</sub>	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t <sub>ENZH</sub>	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t <sub>ENZL</sub>	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t <sub>ENHZ</sub>	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t <sub>ENLZ</sub>	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t <sub>GLH</sub>	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t <sub>GHL</sub>	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t <sub>LSU</sub>	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t <sub>LH</sub>	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>LCO</sub>	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t <sub>ACO</sub>	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d <sub>TLH</sub>	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d <sub>THL</sub>	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

## Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T<sub>J</sub> = 70°C)

1. For dual-module macros, use  $t_{PD1} + t_{RD1} + t_{PDn}$ ,  $t_{CO} + t_{RD1} + t_{PDn}$ , or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.

4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

5. Delays based on 35 pF loading.

## Table 40 •A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions,<br/>VCCA = 4.75 V, T<sub>J</sub> = 70°C)

		–3 Spee	ed	-2 Speed	–1 Sp	eed	Std S	peed	–F S	beed	
Param	eter / Description	Min. Ma	ax.	Min. Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic I	Module Propagation Delays <sup>1</sup>										
t <sub>PD1</sub>	Single Module	1	.4	1.5		1.7		2.0		2.8	ns
t <sub>CO</sub>	Sequential Clock-to-Q	1	.4	1.6		1.8		2.1		3.0	ns
t <sub>GO</sub>	Latch G-to-Q	1	.4	1.5		1.7		2.0		2.8	ns
t <sub>RS</sub>	Flip-Flop (Latch) Reset-to-Q	1	.6	1.7		2.0		2.3		3.3	ns
Logic I	Module Predicted Routing Delays	s <sup>2</sup>									
t <sub>RD1</sub>	FO = 1 Routing Delay	0	).8	0.9		1.0		1.2		1.6	ns
t <sub>RD2</sub>	FO = 2 Routing Delay	1	.0	1.2		1.3		1.5		2.1	ns



# Table 40 •A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued) (Worst-Case Commercial<br/>Conditions, VCCA = 4.75 V, T<sub>J</sub> = 70°C)

			–3 S	peed	–2 SI	beed	–1 Sp	beed	Std S	peed	–F Sp	beed	
Parame	ter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>PWL</sub>	Minimum Pulse Width LOW	FO = 32 FO = 384	3.2 3.7		3.5 4.1		4.0 4.6		4.7 5.4		6.6 7.6		ns ns
t <sub>CKSW</sub>	Maximum Skew	FO = 32 FO = 384		0.3 0.3		0.4 0.4		0.4 0.4		0.5 0.5		0.7 0.7	ns ns
t <sub>SUEXT</sub>	Input Latch External Set-Up	FO = 32 FO = 384	0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		ns ns
t <sub>HEXT</sub>	Input Latch External Hold	FO = 32 FO = 384	2.8 3.2		3.1 3.5		5.5 4.0		4.1 4.7		5.7 6.6		ns ns
t <sub>P</sub>	Minimum Period	FO = 32 FO = 384	4.2 4.6		4.67 5.1		5.1 5.6		5.8 6.4		9.7 10.7		ns ns
f <sub>MAX</sub>	Maximum Frequency	FO = 32 FO = 384		237 215		215 195		198 179		172 156		103 94	MHz MHz



# Table 40 •A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued) (Worst-Case Commercial<br/>Conditions, VCCA = 4.75 V, T<sub>J</sub> = 70°C)

		-3 Speed	-2 Speed	-1 Speed	Std Speed	-F Speed	
Parame	eter / Description	Min. Max.	Units				
TTL Ou	tput Module Timing <sup>4</sup>						
t <sub>DLH</sub>	Data-to-Pad HIGH	2.5	2.8	3.2	3.7	5.2	ns
t <sub>DHL</sub>	Data-to-Pad LOW	3.0	3.3	3.7	4.4	6.1	ns
t <sub>ENZH</sub>	Enable Pad Z to HIGH	2.7	3.0	3.4	4.0	5.6	ns
t <sub>ENZL</sub>	Enable Pad Z to LOW	3.0	3.3	3.8	4.4	6.2	ns
t <sub>ENHZ</sub>	Enable Pad HIGH to Z	5.4	6.0	6.8	8.0	11.2	ns
t <sub>ENLZ</sub>	Enable Pad LOW to Z	5.0	5.6	6.3	7.4	10.4	ns
t <sub>GLH</sub>	G-to-Pad HIGH	2.9	3.2	3.6	4.3	6.0	ns
t <sub>GHL</sub>	G-to-Pad LOW	2.9	3.2	3.6	4.3	6.0	ns
t <sub>LCO</sub>	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	5.7	6.3	7.1	8.4	11.9	ns
t <sub>ACO</sub>	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	8.0	8.9	10.1	11.9	16.7	ns
d <sub>TLH</sub>	Capacitive Loading, LOW to HIGH	0.03	0.03	0.03	0.04	0.06	ns/pF
d <sub>THL</sub>	Capacitive Loading, HIGH to LOW	0.04	0.04	0.04	0.05	0.07	ns/pF



# Table 43 •A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial<br/>Conditions, VCCA = 3.0 V, T<sub>J</sub> = 70°C)

		–3 S	peed	–2 Sj	beed	–1 S	peed	Std S	peed	–F S	peed	
Paramete	er / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Mo	odule Sequential Timing <sup>3, 4</sup>											
t <sub>CO</sub>	Flip-Flop Clock-to-Output		2.1		2.0		2.3		2.7		3.7	ns
t <sub>GO</sub>	Latch Gate-to-Output		3.4		1.9		2.1		2.5		3.4	ns
t <sub>SUD</sub>	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t <sub>HD</sub>	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t <sub>RO</sub>	Flip-Flop (Latch) Reset-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.2		5.8		6.9		9.6		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width	6.1		6.8		7.7		9.0		12.6		ns
Input Mo	dule Propagation Delays											
t <sub>INPY</sub>	Input Data Pad-to-Y		1.4		1.6		1.8		2.2		3.0	ns
t <sub>INGO</sub>	Input Latch Gate-to-Output		1.8		1.9		2.2		2.6		3.6	ns
t <sub>INH</sub>	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t <sub>ILA</sub>	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns



# Table 44 •A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions,<br/>VCCA = 4.75 V, T<sub>J</sub> = 70°C)

			–3 S	peed	–2 Sp	beed	–1 Sp	beed	Std S	peed	–F Sp	beed	
Paramet	er / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>SUEXT</sub>	Input Latch External Set-Up	FO = 32 FO = 635	0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		ns ns
t <sub>HEXT</sub>	Input Latch External Hold	FO = 32 FO = 635	2.8 3.3		3.2 3.7		3.6 4.2		4.2 4.9		5.9 6.9		ns ns
t <sub>P</sub>	Minimum Period (1/f <sub>MAX</sub> )	FO = 32 FO = 635	5.5 6.0		6.1 6.6		6.6 7.2		7.6 8.3		12.7 13.8		ns ns
f <sub>MAX</sub>	Maximum Datapath Frequency	FO = 32 FO = 635		180 166		164 151		151 139		131 121		79 73	MHz MHz
TTL Out	put Module Timing <sup>5</sup>												
t <sub>DLH</sub>	Data-to-Pad HIGH			2.6		2.8		3.2		3.8		5.3	ns
t <sub>DHL</sub>	Data-to-Pad LOW			3.0		3.3		3.7		4.4		6.2	ns
t <sub>ENZH</sub>	Enable Pad Z to HIG	Н		2.7		3.0		3.3		3.9		5.5	ns
t <sub>ENZL</sub>	Enable Pad Z to LOV	V		3.0		3.3		3.7		4.3		6.1	ns
t <sub>ENHZ</sub>	Enable Pad HIGH to	Z		5.3		5.8		6.6		7.8		10.9	ns



Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

### TDI, I/OTest Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

### TDO, I/OTest Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

### TMS, I/OTest Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a  $10k\Omega$  pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

### VCC, Supply Voltage

Input supply voltage for 40MX devices

### VCCA, Supply Voltage

Supply voltage for array in 42MX devices

### VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

### WD, I/OWide Decode Output

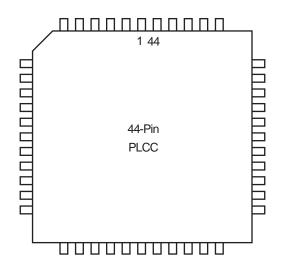
When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.



## 4 Package Pin Assignments

The following figures and tables give the details of the package pin assignments.

Figure 38 • PL44



### Table 47 • PL44

PL44		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	I/O	I/O
3	VCC	VCC
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	GND	GND
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCC	VCC
15	I/O	I/O
16	VCC	VCC
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O



Table 48 • PL68	Table	48	•	PL68
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PL68		
Pin Number	A40MX02 Function	A40MX04 Function
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	GND	GND
67	I/O	I/O
68	I/O	I/O

Figure 40 • PL84

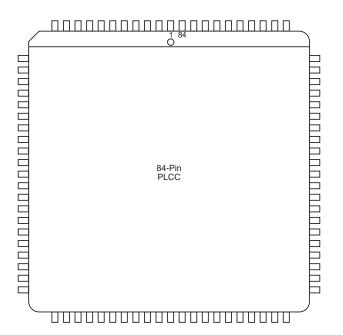


Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	I/O	I/O	I/O	I/O
2	I/O	CLKB, I/O	CLKB, I/O	CLKB, I/O
3	I/O	I/O	I/O	I/O
4	VCC	PRB, I/O	PRB, I/O	PRB, I/O
5	I/O	I/O	I/O	WD, I/O
6	I/O	GND	GND	GND
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	WD, I/O
9	I/O	I/O	I/O	WD, I/O



### Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
56	VCC	VCC	I/O	I/O
57	I/O	I/O	GND	GND
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	I/O	I/O	I/O	I/O
61	I/O	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	GND	GND	I/O	I/O
64	I/O	I/O	LP	LP
65	I/O	I/O	VCCA	VCCA
66	I/O	I/O	VCCI	VCCI
67	I/O	I/O	VCCA	VCCA
68	I/O	I/O	I/O	I/O
69	VCC	VCC	I/O	I/O
70	I/O	I/O	I/O	I/O
71	I/O	I/O	I/O	I/O
72	I/O	I/O	GND	GND
73	I/O	I/O	I/O	I/O
74	I/O	I/O	I/O	I/O
75	I/O	I/O	I/O	I/O
76	I/O	I/O	I/O	I/O
77	NC	NC	I/O	I/O
78	NC	NC	I/O	I/O
79	NC	NC	SDI, I/O	SDI, I/O
80	NC	I/O	I/O	I/O
81	NC	I/O	I/O	I/O
82	NC	I/O	I/O	I/O
83	I/O	I/O	I/O	I/O
84	I/O	I/O	GND	GND
85	I/O	I/O	I/O	I/O
86	GND	GND	I/O	I/O
87	GND	GND	PRA, I/O	PRA, I/O
88	I/O	I/O	I/O	I/O
89	I/O	I/O	CLKA, I/O	CLKA, I/O
90	CLK, I/O	CLK, I/O	VCCA	VCCA
91	I/O	I/O	I/O	I/O
92	MODE	MODE	CLKB, I/O	CLKB, I/O



### Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
132	VCCI	VCCI	VCCI
133	VCCA	VCCA	VCCA
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	VCCA	VCCA	VCCA
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	I/O	I/O	I/O
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	I/O	I/O	I/O
146	NC	I/O	I/O
147	NC	I/O	I/O
148	NC	I/O	I/O
149	NC	I/O	I/O
150	GND	GND	GND
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	I/O	I/O	I/O
156	I/O	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	SDI, I/O	SDI, I/O	SDI, I/O
160	I/O	I/O	I/O
161	I/O	WD, I/O	WD, I/O
162	I/O	WD, I/O	WD, I/O
163	I/O	I/O	I/O
164	VCCI	VCCI	VCCI
165	NC	I/O	I/O
166	NC	I/O	I/O
167	I/O	I/O	I/O
168	I/O	WD, I/O	WD, I/O



CQ208	
Pin Number	A42MX36 Function
1	GND
2	VCCA
3	MODE
4	I/O
5	I/O
6	I/O
7	I/O
3	I/O
)	I/O
10	I/O
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	VCCA
18	I/O
9	I/O
20	I/O
21	I/O
22	GND
23	I/O
24	I/O
25	I/O
26	I/O
27	GND
28	VCCI
29	VCCA
30	I/O
31	I/O
32	VCCA
33	I/O
34	I/O
35	I/O
36	I/O



CQ208	
Pin Number	A42MX36 Function
74	I/O
75	I/O
76	I/O
77	I/O
78	GND
79	VCCA
80	VCCI
81	I/O
32	I/O
83	I/O
34	I/O
35	WD, I/O
36	WD, I/O
87	I/O
38	I/O
89	I/O
90	I/O
91	QCLKB, I/O
92	I/O
93	WD, I/O
94	WD, I/O
95	I/O
96	I/O
97	I/O
98	VCCI
99	I/O
100	WD, I/O
101	WD, I/O
102	I/O
103	TDO, I/O
104	I/O
105	GND
106	VCCA
107	I/O
108	I/O
109	I/O
110	I/O



Table 60 • E	3G272
BG272	
Pin Number	A42MX36 Function
C3	GND
C4	I/O
C5	WD, I/O
C6	I/O
C7	QCLKC, I/O
C8	I/O
C9	I/O
C10	CLKB
C11	PRA, I/O
C12	WD, I/O
C13	I/O
C14	QCLKD, I/O
C15	I/O
C16	WD, I/O
C17	SDI, I/O
C18	I/O
C19	I/O
C20	I/O
D1	I/O
D2	I/O
D3	I/O
D4	I/O
D5	VCCI
D6	I/O
D7	I/O
D8	VCCA
D9	WD, I/O
D10	VCCI
D11	I/O
D12	VCCI
D13	I/O
D14	VCCI
D15	I/O
D16	VCCA
D17	GND
D18	I/O
D19	I/O

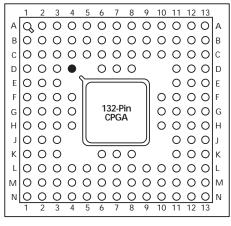


Table 60 • BG	272
BG272	
Pin Number	A42MX36 Function
D20	I/O
E1	I/O
E2	I/O
E3	I/O
E4	VCCA
E17	VCCI
E18	I/O
E19	I/O
E20	I/O
F1	I/O
F2	I/O
F3	I/O
F4	VCCI
F17	I/O
F18	I/O
F19	I/O
F20	I/O
G1	I/O
G2	I/O
G3	I/O
G4	VCCI
G17	VCCI
G18	I/O
G19	I/O
G20	I/O
H1	I/O
H2	I/O
H3	I/O
H4	VCCA
H17	I/O
H18	I/O
H19	I/O
H20	I/O
J1	I/O
J2	I/O
J3	I/O
J4	VCCI



Table 60 •         BG272           BG272		
Y13	I/O	
Y14	I/O	
Y15	I/O	
Y16	I/O	
Y17	I/O	
Y18	WD, I/O	
Y19	GND	
Y20	GND	

### Figure 52 • PG132



Orientation Pin

#### Table 61 • PG132

PG132	
A42MX09 Function	
PMPOUT	
I/O	
MODE	
I/O	